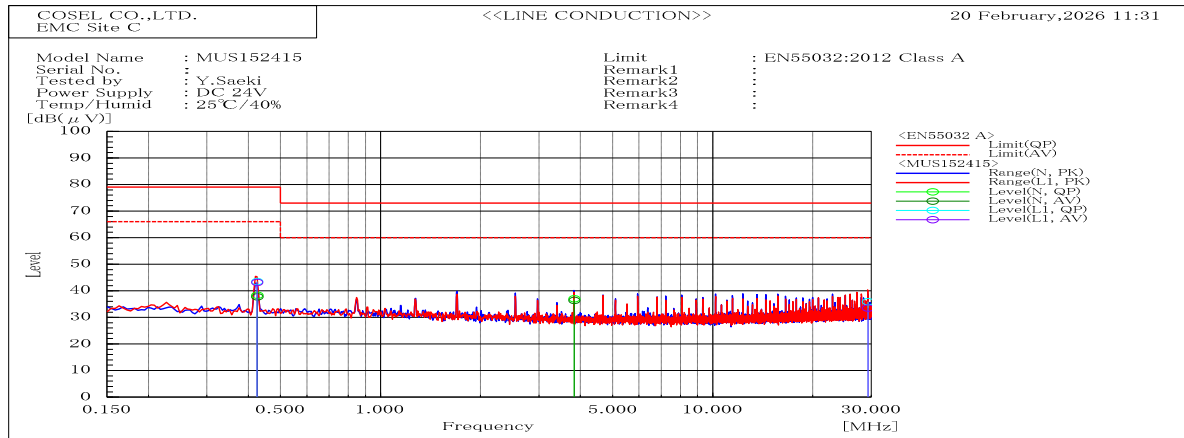
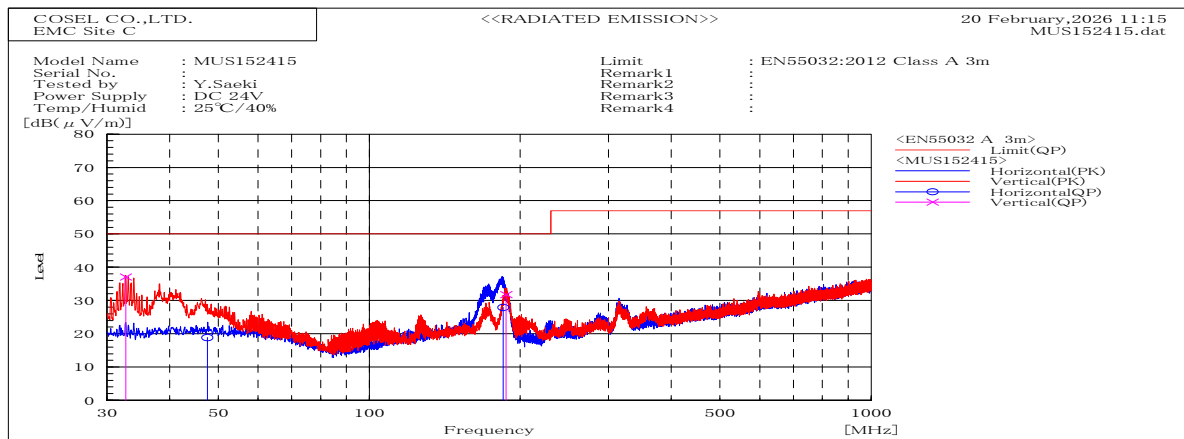


DATA SHEET

Model	MUS152415	Date	15-May-26
Test	EMI	Temp.	25 degreeC
	Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki



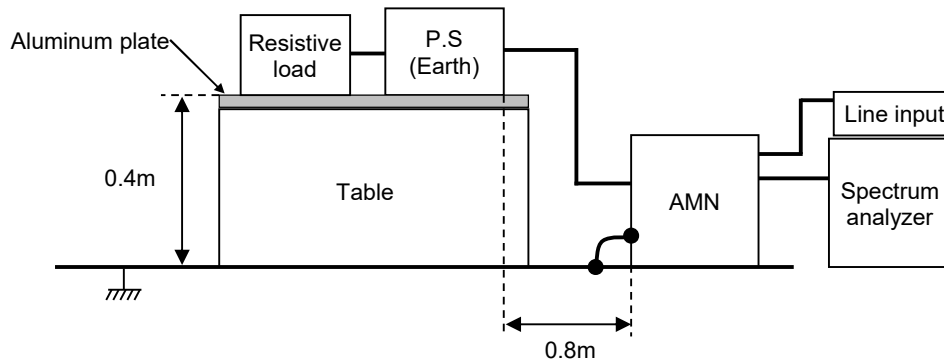
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.426	N	38.4	37.8	79	66	40.6	28.2	Pass	
3.834	N	37.1	36.4	73	60	35.9	23.6	Pass	
0.425	L1	43.5	43.2	79	66	35.5	22.8	Pass	
29.366	L1	35.9	33.5	73	60	37.1	26.5	Pass	



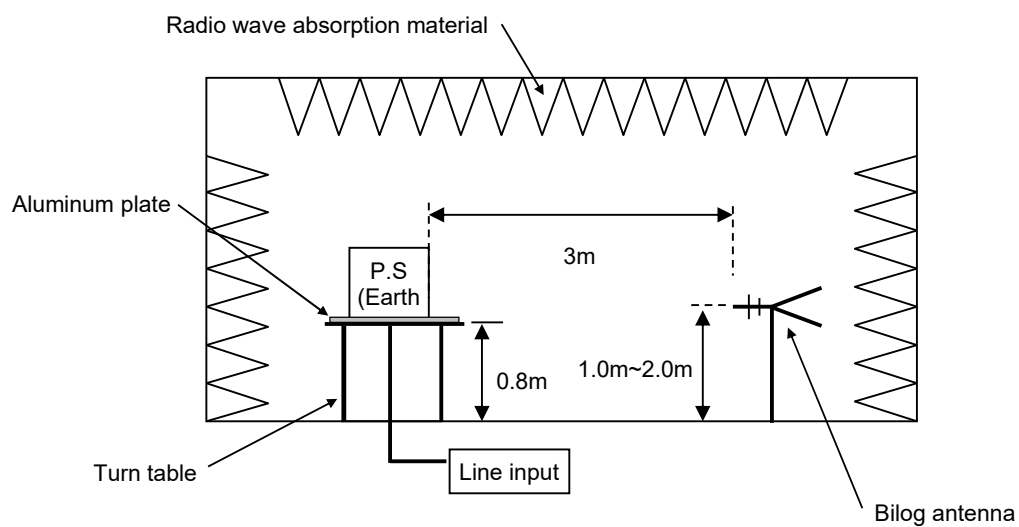
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB		cm	deg	
			QP	QP	QP				
47.575	H	Stable	18.8	50	31.2	Pass	101.5	0	
184.906	H	Stable	27.9	50	22.1	Pass	200	19.5	
32.724	V	Stable	37.1	50	12.9	Pass	100.3	307.4	
187.438	V	Stable	31.8	50	18.2	Pass	100	18.1	

DATA SHEET		Date	15-May-26
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Saeki

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name: MUS15□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

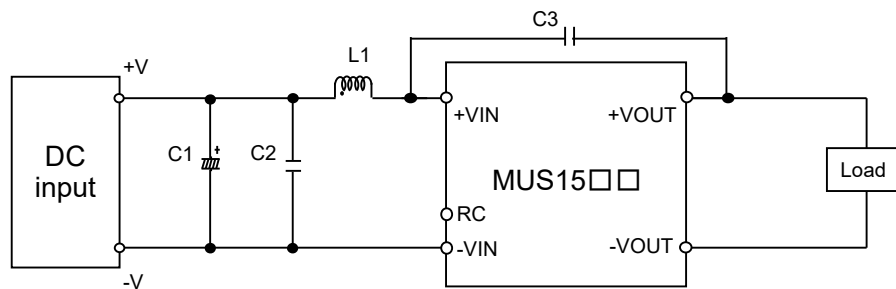


Fig.1 MUS15□□ Testing circuitry

C1 :	MUS1524□	50V 47 μ F Electric capacitor (UPWseries NICHICON)
	MUS1548□	-
C2 :	MUS1524□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1548□	100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
C3 :	MUS15□□	2000V 1000pF Ceramic capacitor (C3225X7S3D102K200AA TDK)
L1 :	MUS1524□	1600mA 22 μ H Inductor (LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1548□	1100mA 47 μ H Inductor (LQH5BPN470M38 MURATA MANUFACTURING)